Accepted Manuscript

Resonant inelastic X-ray scattering of tantalum double perovskite structures

Ju Hyun Oh, Jung Ho Kim, Jung Hyeon Jeong, Seo Hyoung Chang

PII: S1567-1739(18)30138-X

DOI: 10.1016/j.cap.2018.05.014

Reference: CAP 4755

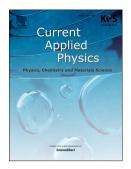
To appear in: Current Applied Physics

Received Date: 15 April 2018

Accepted Date: 11 May 2018

Please cite this article as: J.H. Oh, J.H. Kim, J.H. Jeong, S.H. Chang, Resonant inelastic X-ray scattering of tantalum double perovskite structures, *Current Applied Physics* (2018), doi: 10.1016/j.cap.2018.05.014.

This is a PDF file of an unedited manuscript that has been accepted for publication. As a service to our customers we are providing this early version of the manuscript. The manuscript will undergo copyediting, typesetting, and review of the resulting proof before it is published in its final form. Please note that during the production process errors may be discovered which could affect the content, and all legal disclaimers that apply to the journal pertain.



ACCEPTED MANUSCRIPT

Resonant Inelastic X-ray Scattering of Tantalum Double Perovskite Structures

Ju Hyun Oh¹, Jung Ho Kim², Jung Hyeon Jeong¹, Seo Hyoung Chang^{1,3*}

¹Department of Physics, Pukyong National University, Busan 48513, South Korea

²Advanced Photon Source, Argonne National Laboratory, Lemont 60439, United States

³Department of Physics, Chung-Ang University, Seoul 06974, South Korea

In this paper, we investigated the electronic structures and defect states of SrLaMgTaO₆ (SLMTO) double perovskite structures by using resonant inelastic x-ray scattering. Recently, Eu³⁺ doped SLMTO red phosphors have been vigorously investigated due to their higher red emission efficiency compared to commercial white light emitting diodes (W-LED). However, a comprehensive understanding on the electronic structures and defect states of host SLMTO compounds, which are specifically related to the W-LED and photoluminescence (PL), is far from complete. Here, we found that the PL spectra of SLMTO powder compounds sintered at a higher temperature, 1400°C, were weaker in the blue emission regions (at around 400 nm) and became enhanced in near infrared (NIR) regions compared to those sintered at 1200°C. To elucidate the difference of the PL spectra, we performed resonant inelastic x-ray spectroscopy (RIXS) at Ta L-edge. Our RIXS result implies that the microscopic origin of different PL spectra is not relevant to the Ta-related defects and oxygen vacancies.

Keywords: Resonant Inelastic X-ray Scattering, SrLaMgTaO₆, Double Perovskites, Light Emitting Diodes

^{*} e-mail: cshyoung@pknu.ac.kr and cshyoung@cau.ac.kr

Download English Version:

https://daneshyari.com/en/article/11008819

Download Persian Version:

https://daneshyari.com/article/11008819

Daneshyari.com